

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 218474US2		SERIAL NO. New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Naoki KUSUNOKI, et al.			
				FILING DATE Herewith		GROUP	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
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	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
AW	T. KUROI, et al., "STRESS ANALYSIS OF SHALLOW TRENCH ISOLATION FOR 256MDRAM AND BEYOND", IEEE, March 1998, (4 pages)						
AX	F. OOTSUKA, et al., "A HIGHLY DENSE, HIGH-PERFORMANCE 130nm NODE CMOS TECHNOLOGY FOR LARGE SCALE SYSTEM-ON-A-CHIP APPLICATIONS", IEEE April 2000, (4 pages)						
AY							
AZ						<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>[Signature]</i>					Date Considered 7/8/05		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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